Device Modeling Report

COMPONENTS: Power MOSFET (Professional)
PART NUMBER: TPC6003
MANUFACTURER: TOSHIBA
Body Diode (Professional) / ESD Protection Diode

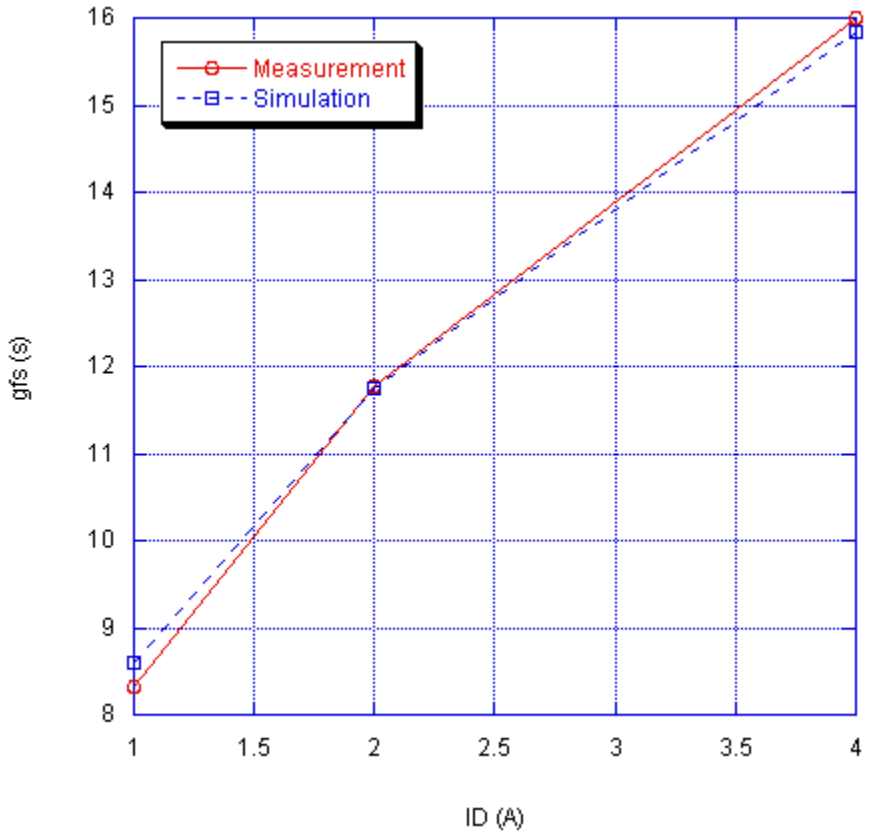
Bee Technologies Inc.

MOSFET MODEL

Pspice model parameter	Model description
LEVEL	
L	Channel Length
W	Channel Width
KP	Transconductance
RS	Source Ohmic Resistance
RD	Ohmic Drain Resistance
VTO	Zero-bias Threshold Voltage
RDS	Drain-Source Shunt Resistance
TOX	Gate Oxide Thickness
CGSO	Zero-bias Gate-Source Capacitance
CGDO	Zero-bias Gate-Drain Capacitance
CBD	Zero-bias Bulk-Drain Junction Capacitance
MJ	Bulk Junction Grading Coefficient
PB	Bulk Junction Potential
FC	Bulk Junction Forward-bias Capacitance Coefficient
RG	Gate Ohmic Resistance
IS	Bulk Junction Saturation Current
N	Bulk Junction Emission Coefficient
RB	Bulk Series Resistance
PHI	Surface Inversion Potential
GAMMA	Body-effect Parameter
DELTA	Width effect on Threshold Voltage
ETA	Static Feedback on Threshold Voltage
THETA	Modility Modulation
KAPPA	Saturation Field Factor
VMAX	Maximum Drift Velocity of Carriers
XJ	Metallurgical Junction Depth
UO	Surface Mobility

Transconductance Characteristic

Circuit Simulation Result

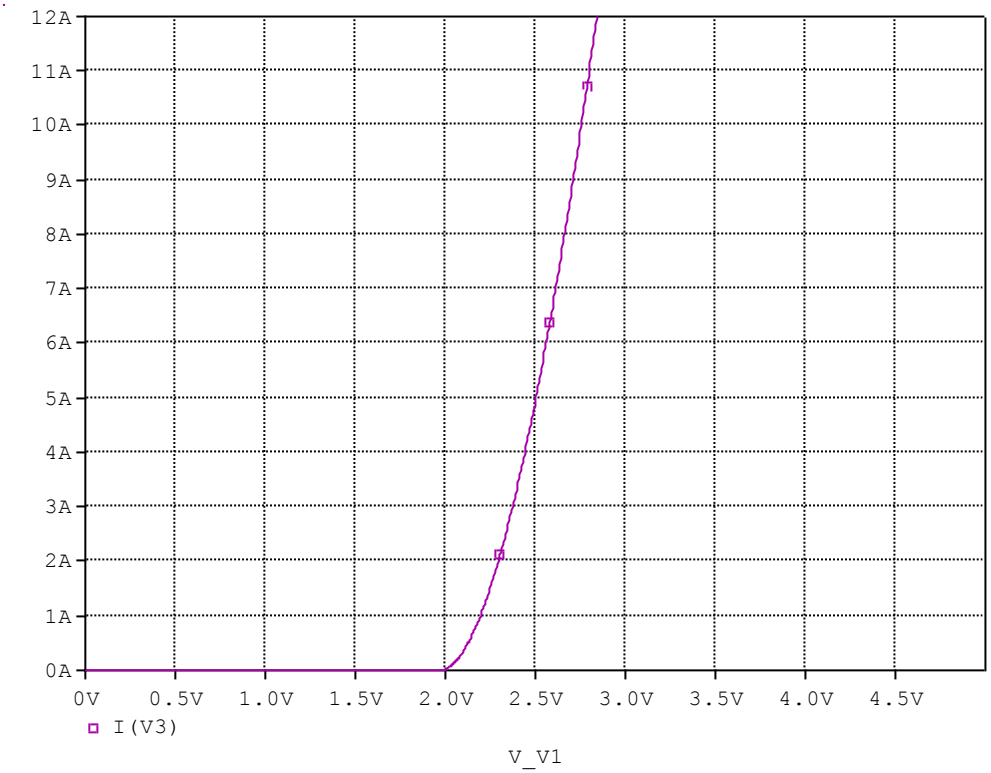


Comparison table

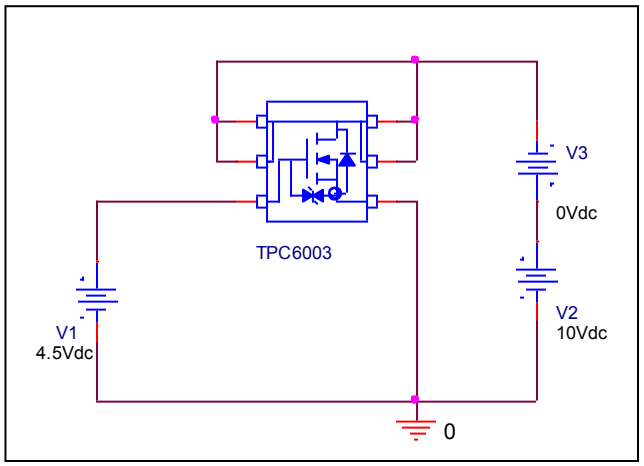
I_D(A)	V_{GS}(V)		Error (%)
	Measurement	Simulation	
1.000	8.333	8.606	3.276
2.000	11.764	11.749	-0.129
4.000	16.000	15.835	-1.031

Vgs-Id Characteristic

Circuit Simulation result

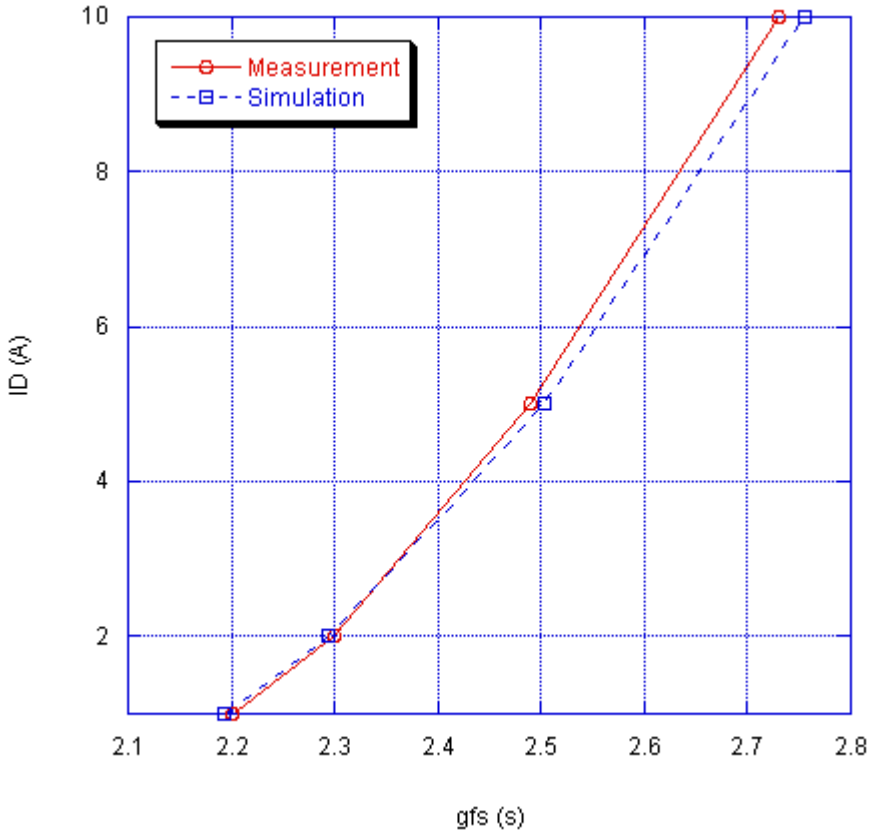


Evaluation circuit



Comparison Graph

Circuit Simulation Result

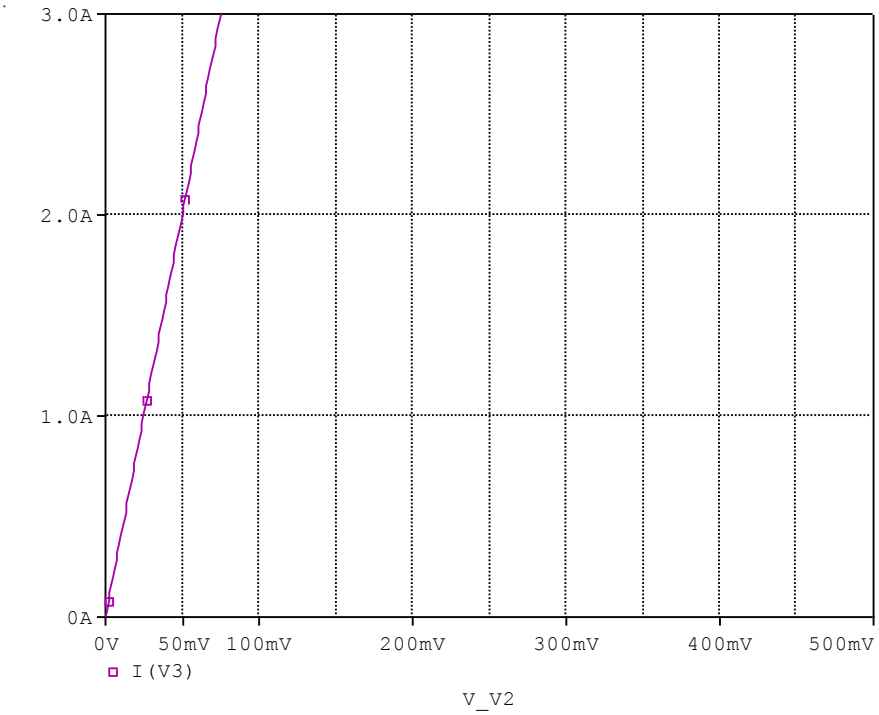


Simulation Result

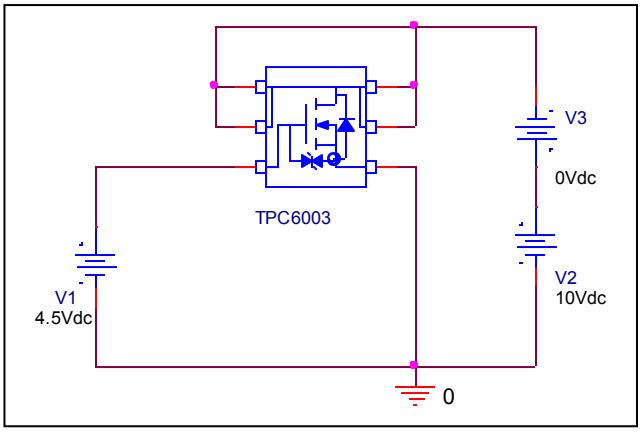
I_D(A)	V_{GS}(V)		Error (%)
	Measurement	Simulation	
1.000	2.200	2.194	-0.259
2.000	2.300	2.294	-0.243
5.000	2.490	2.503	0.538
10.000	2.730	2.755	0.923

Id-Rds(on) Characteristic

Circuit Simulation result



Evaluation circuit

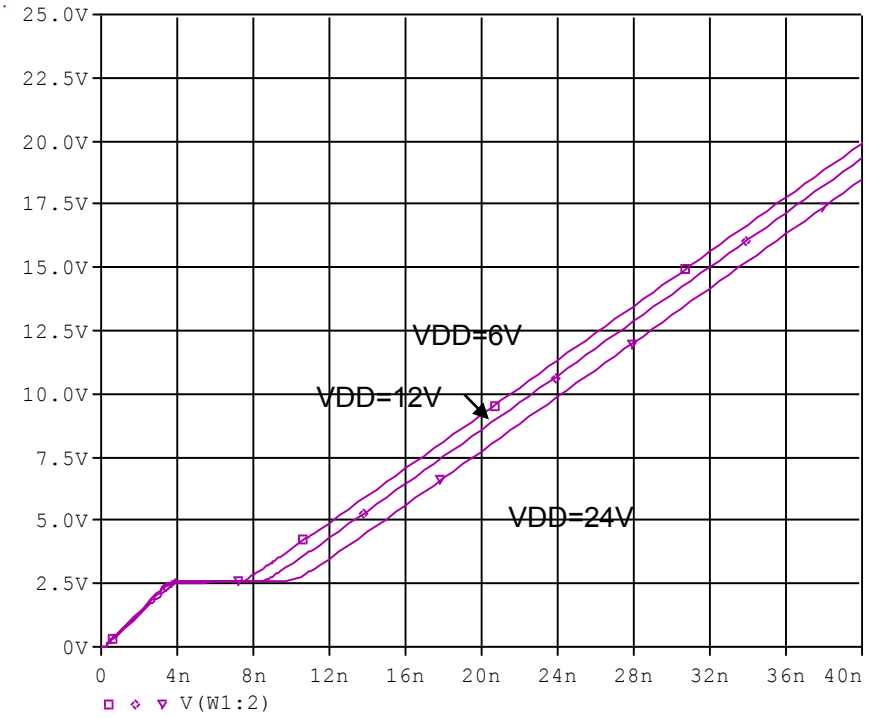


Simulation Result

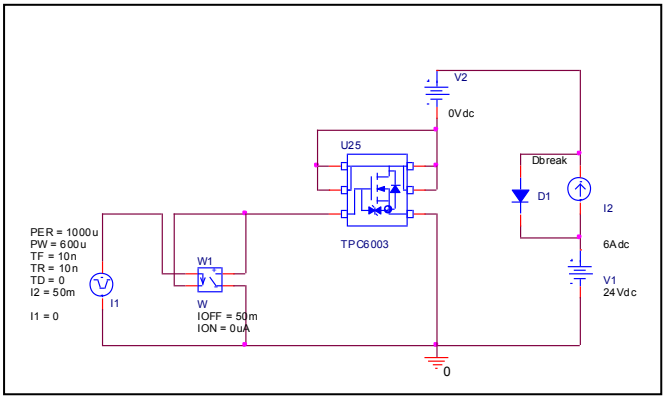
I_D=3, V_{GS}=4.5V	Measurement		Simulation		Error (%)
R_{DS} (on)	25.00	mΩ	25.00	mΩ	0.00

Gate Charge Characteristic

Circuit Simulation result



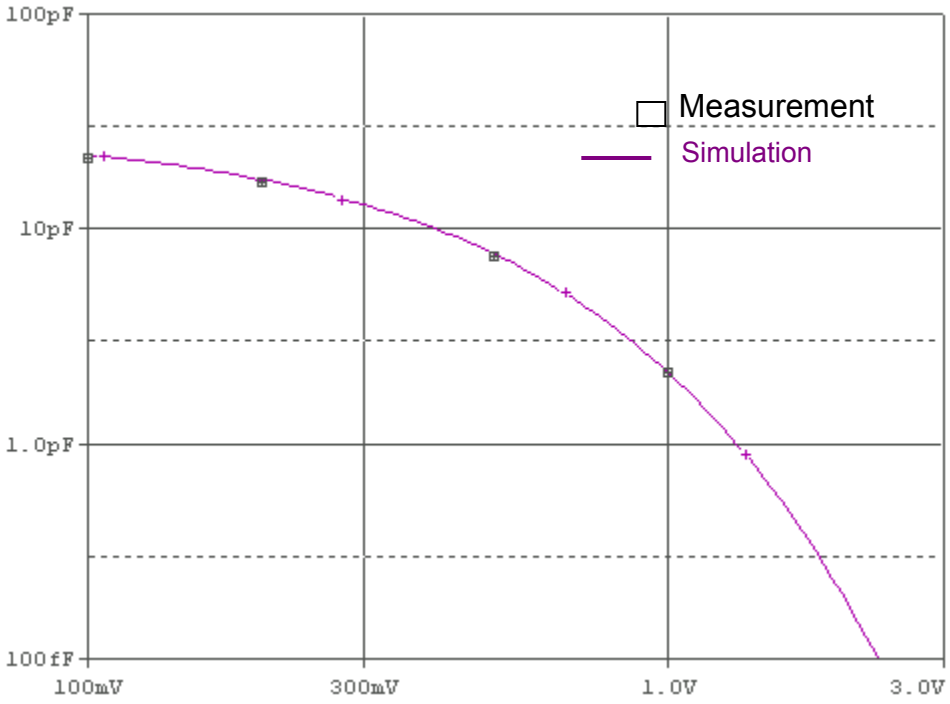
Evaluation circuit



Simulation Result

V_{DD}=24V,I_D=6A ,V_{GS}=5V	Measurement		Simulation		Error (%)
Qgs	3.70	nC	3.70	nC	0.000
Qgd	6.32	nC	6.30	nC	-0.316
Qg	24.00	nC	24.15	nC	0.625

Capacitance Characteristic

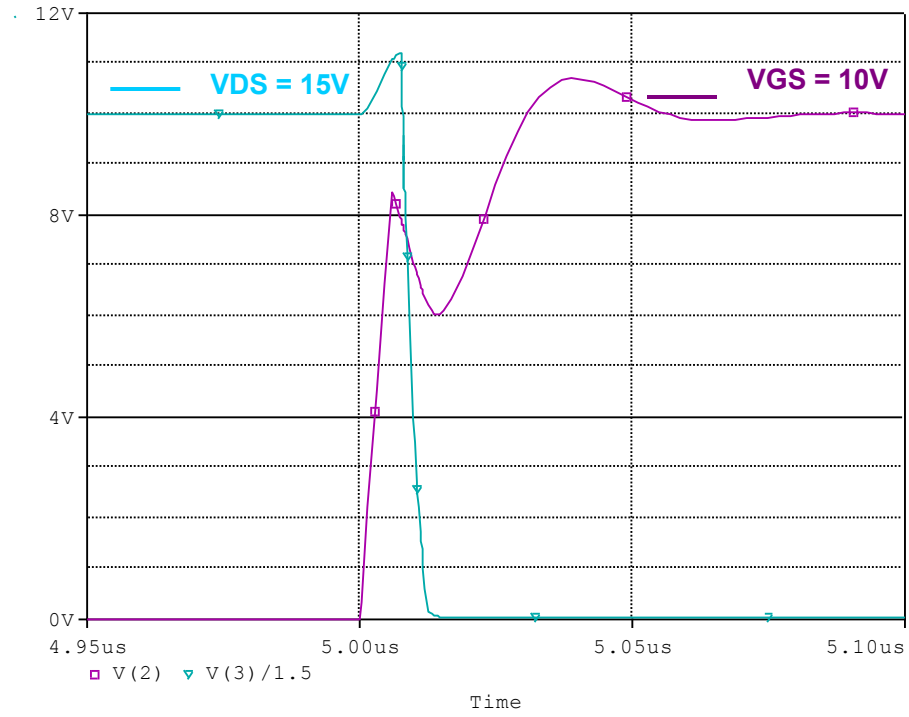


Simulation Result

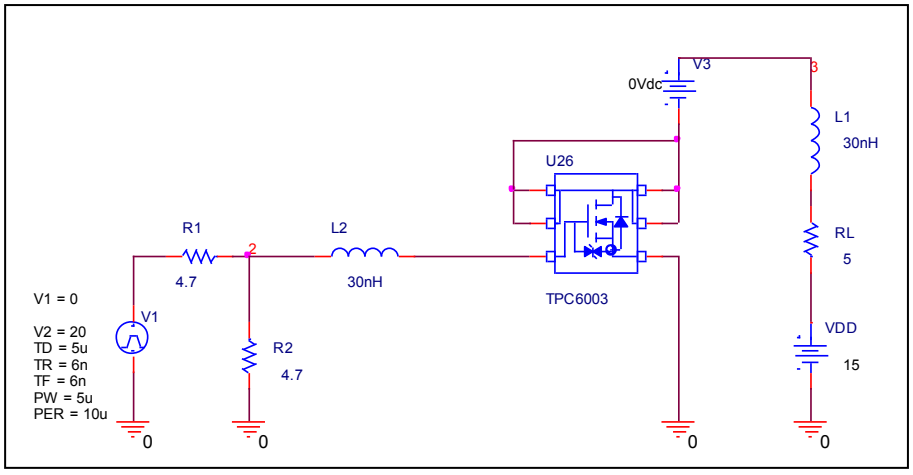
V_{DS}(V)	Cbd(pF)		Error(%)
	Measurement	Simulation	
0.100	22.000	22.075	0.341
0.200	17.000	16.900	-0.588
0.500	7.700	7.620	-1.039
1.000	2.200	2.170	-1.364

Switching Time Characteristic

Circuit Simulation result



Evaluation circuit

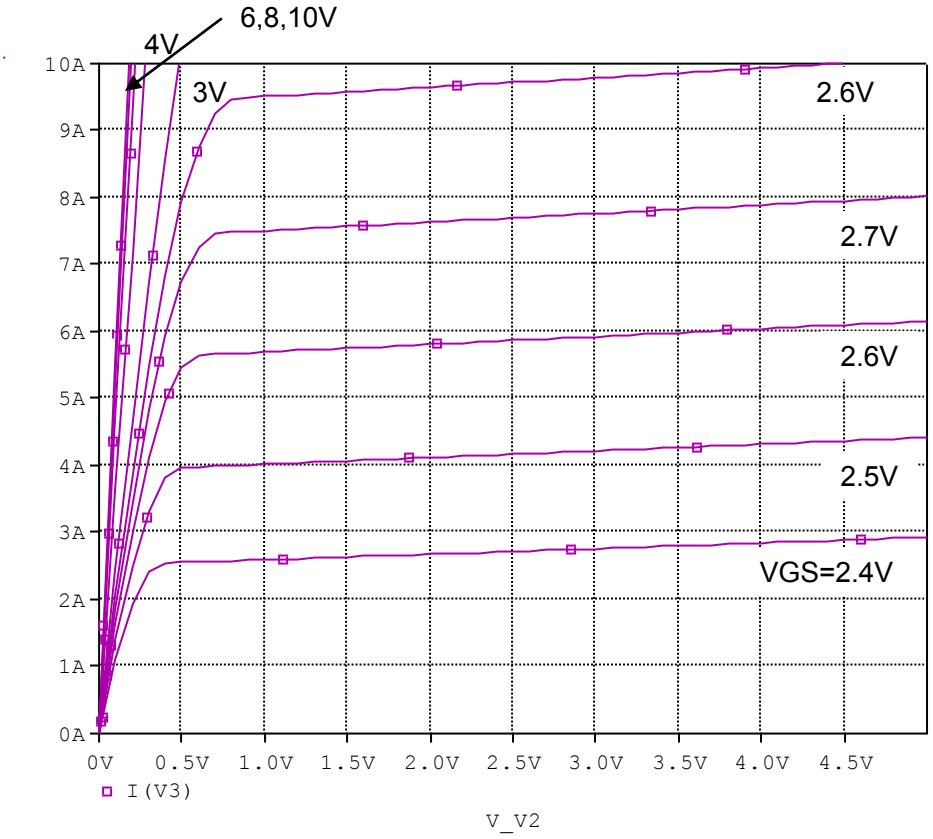


Simulation Result

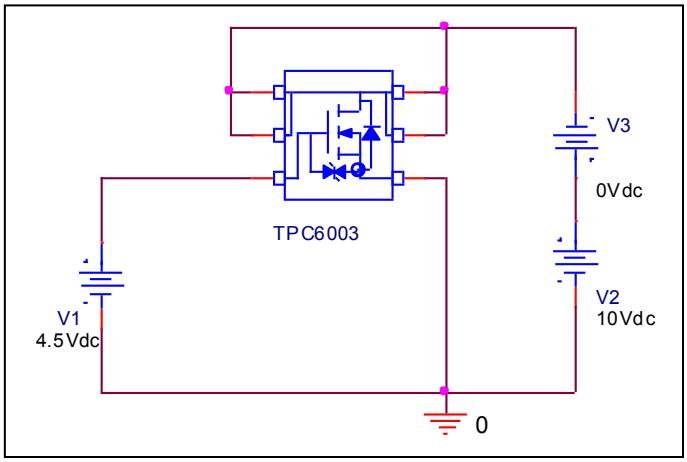
I_D=3A, V_{DD}=15V V_{GS}=0/5V	Measurement		Simulation		Error(%)
td (on)	11.000	ns	11.014	ns	0.127

Output Characteristic

Circuit Simulation result

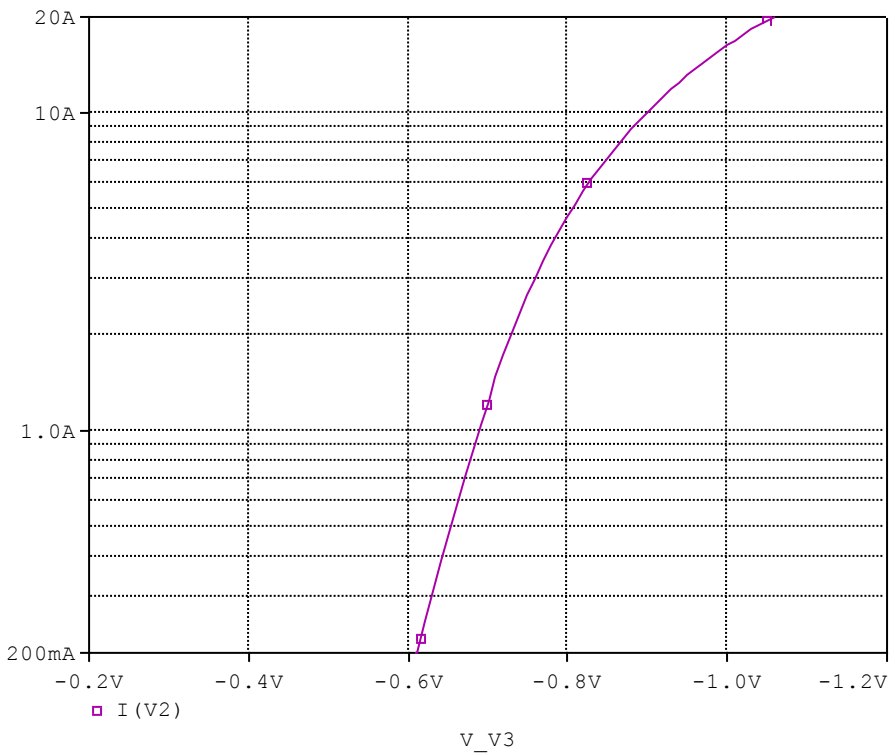


Evaluation circuit

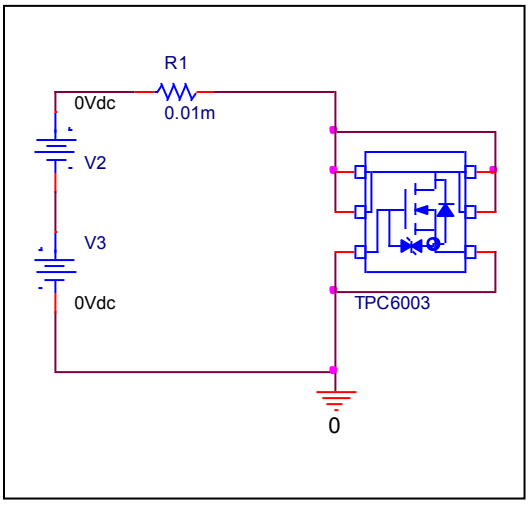


Forward Current Characteristic

Circuit Simulation Result

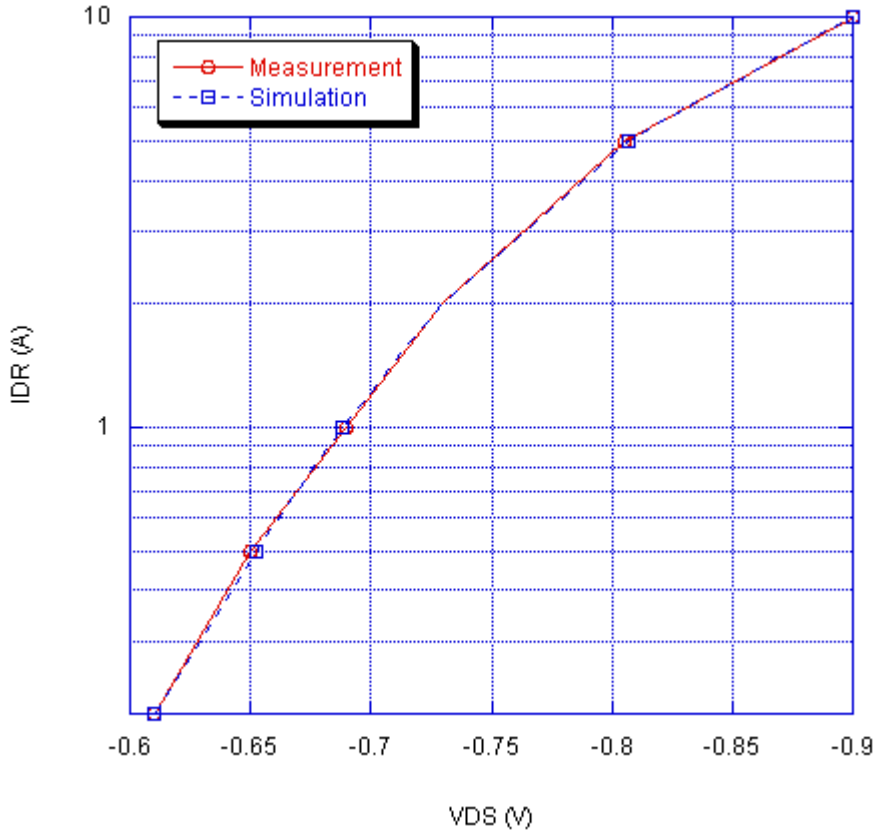


Evaluation Circuit



Comparison Graph

Circuit Simulation Result

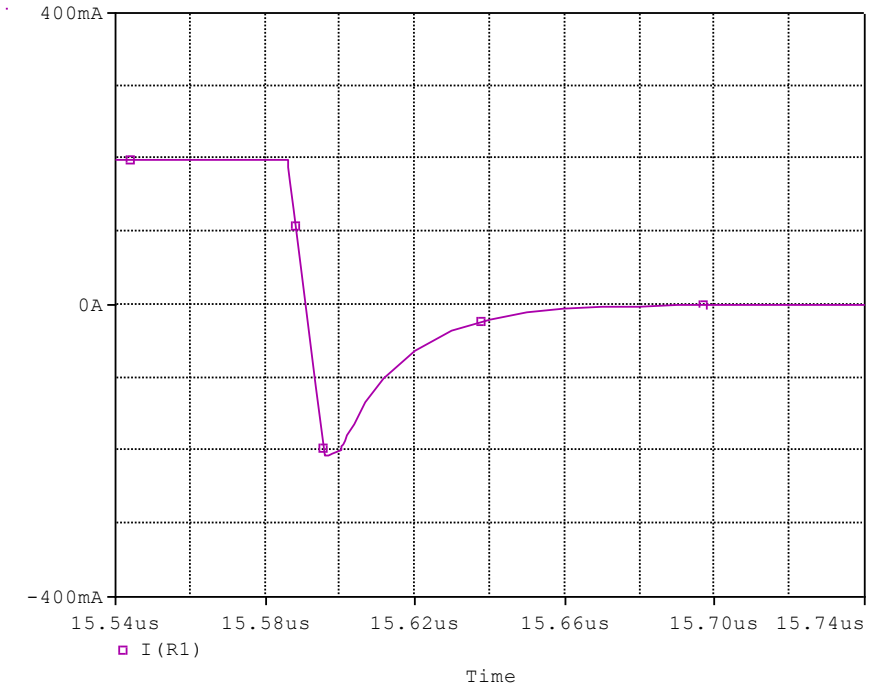


Simulation Result

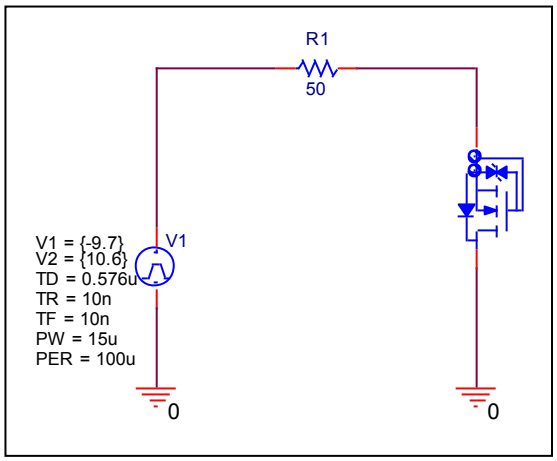
Ifwd(A)	Vfwd(V) Measurement	Vfwd(V) Simulation	%Error
0.200	-0.610	-0.610	-0.052
0.500	-0.650	-0.652	0.328
1.000	-0.690	-0.688	-0.329
2.000	-0.730	-0.730	-0.045
5.000	-0.805	-0.807	0.203
10.000	-0.900	-0.900	-0.041

Reverse Recovery Characteristic

Circuit Simulation Result



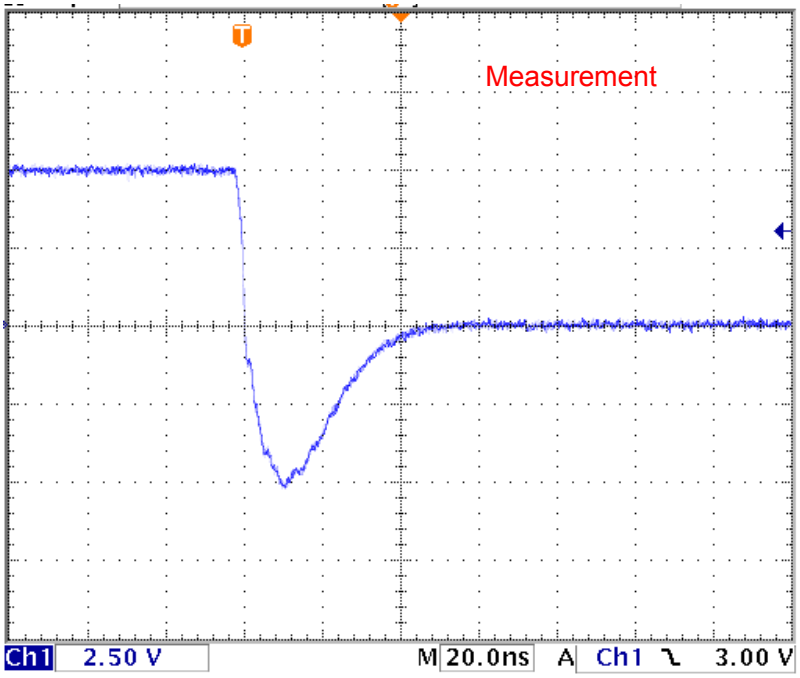
Evaluation circuit



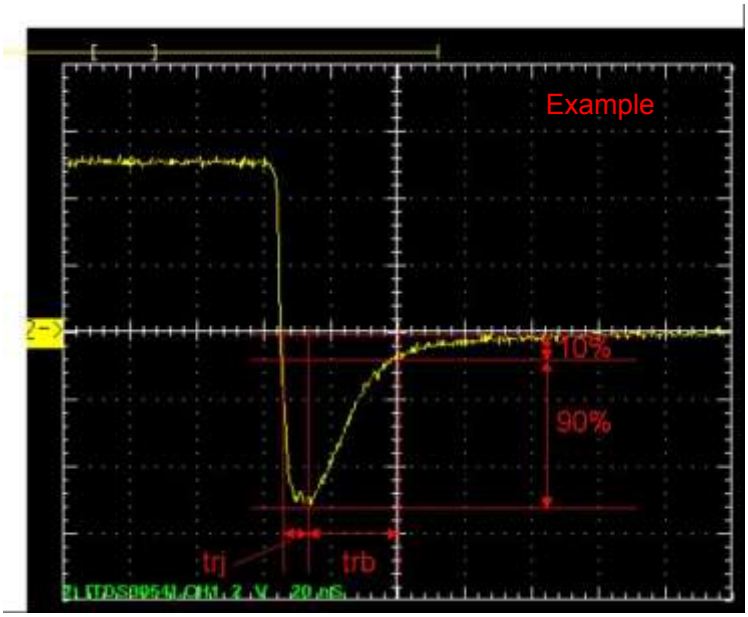
Compare Measurement vs. Simulation

	Measurement		Simulation		Error(%)
trj	8.800	ns	8.802	ns	0.023
trb	39.200	ns	39.091	ns	-0.278
trr	48.000	ns	47.893	ns	-0.223

Reverse Recovery Characteristic Reference



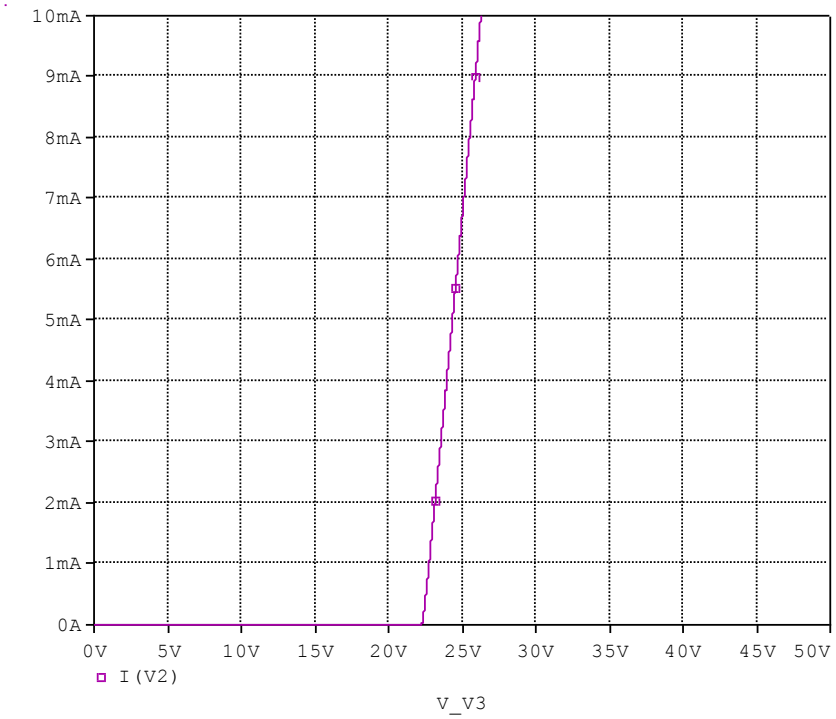
trj=8.8(ns)
trb=39.2(ns)
Conditions:Ifwd=Irev=0.2(A),Rl=50



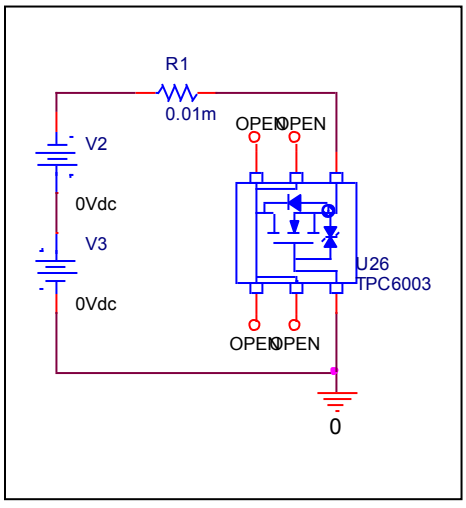
Relation between trj and trb

Zener Voltage Characteristic

Circuit Simulation Result



Evaluation Circuit



Zener Voltage Characteristic Reference